

PatternMatching

The purpose of the pattern matching routine is to generate defocused (or focused) model images of single dipole emitters as imaged by a standard wide-field microscope on a CCD, and to use these generate model images for identifying and localizing corresponding images in a measure wide-field image. First at all, the routine reads in the measured image to process. This is done in the first four lines, for example by

```
if exist('im')==0
    im = double(imread('c:\Joerg\example.png'));
    im = im(100:end-101,100:end-100);
end
```

where one first asks whether the image `im` is already within working memory, and if not, it reads the image from the specified location (here at `c:\Joerg\example.png`).

Next, the routine calculates the model images of a single molecule emitter for a discrete set of possible orientations. This is done by

```
model = PatternGeneration(z, NA, n0, n, n1, d0, d, d1, lamem, mag,
    focus, atf, ring, pixel, nn, be_res, al_res, pic);
```

PatternGeneration calculates the images of an oscillating electric dipole emitter (e.g. single molecule) within a planar stratified structure as imaged by a high-aperture microscope onto a CCD chip. The emitter is assumed to be located at the bottom interface of a layer with refractive index n and thickness d that is sandwiched between two stacks of layers with refractive indices $n_{1,1}$ through $n_{1,k1}$ and thickness values $d_{1,1}$ through $d_{1,k1-1}$ (bottom stack, from bottom to top) and refractive indices $n_{2,1}$ through $n_{2,k2}$ and thickness values $d_{2,1}$ through $d_{2,k2-1}$ (top stack, from bottom to top).

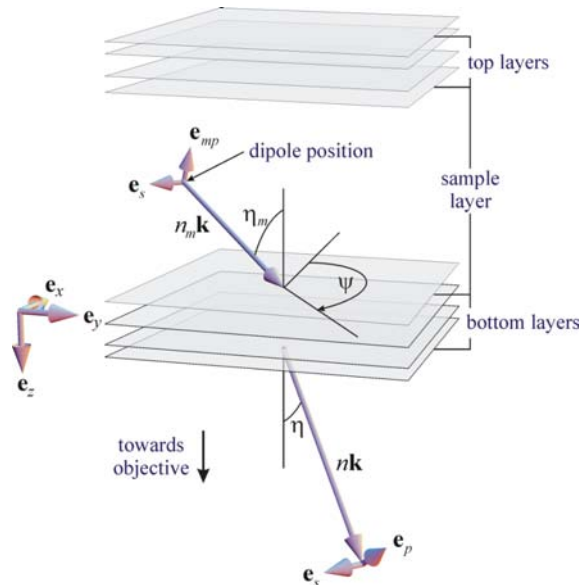


Fig.1: Geometry of the sample space: the sample solution is stacked between stacks of layers with homogeneous optical properties.

Images are calculated for all possible orientations of the emitter defined by the two angles β and α , where β is the inclination towards the optical axis and α the azimuthal

angle around the optical axis. The values of θ and ϕ are varied incrementally by steps defined by `be_res` (β) and `al_res` (α). The image is calculated for a CCD camera with assumed pixel size of `pixel` in μm , the generated images have square size of $(2*\text{nn} + 1)*(2*\text{nn} + 1)$.

The following table gives a detailed description of the input and output variables.

Input variables:

z	– position of emitter above bottom of its layer in μm ;
NA	– numerical aperture;
n1	– vector of refractive indices of the stack below the molecule's layer;
n	– refractive index of the molecule's layer;
n2	– vector of refractive indices of the stack above the molecule's layer;
d1	– vector of layer thickness values of the stack below the molecule's layer ($\text{length}(\text{d1}) = \text{length}(\text{n1}) - 1$);
d	– thickness of molecule's layer;
d2	– vector of layer thickness values of the stack above the molecule's layer ($\text{length}(\text{d2}) = \text{length}(\text{n2}) - 1$).
lamem	– center emission wavelength in μm ;
mag	– imaging magnification;
focus	– defocusing value in μm , giving the distance the objective is moved out of focus <i>towards</i> the sample;
atf	– correction vector for coverslide thickness effects. If atf = [], no coverslide effects are taken into account. If atf is a 2-element vector, the first is the refractive index of the coverslide glass, the second the deviation (in μm) of the coverslide thickness from its design value;
ring	– optional parameter for a potential phase plate (default []);
pixel	– side length of one pixel in μm ;
nn	– the image is calculated over $(2*\text{nn} + 1)*(2*\text{nn} + 1)$ pixels (default nn = 10)
be_res	– increment in polar angle (default 10°)
al_res	– increment in azimuthal angle (default 10°)
pic	– if non-zero and non-empty, the calculated images are shown in a figure (default 0)

Output variable:

model – structure with the following fields:

model.rho	– radial coordinate
model.theta	– vector of polar angles
model.phi	– vector of azimuthal angles
model.mask	– three-dimensional field of images: model.mask(:, :, j) is the image corresponding to the emitter orientation with $\beta = \text{model.theta}(j)$ and $\alpha = \text{model.phi}(j)$;

The next and final step is to locate modeled patterns within the measured image. This is done by the commands

```
bck = Disk((size(model.mask,1)-1)/2);
[err, bim, cim, sim, xc, yc, bc, cc, sc, len, imm] = FindPattern(im,model.mask,bck,bck);
```

where the first line calculates a background pattern (uniform disc with a radius `nn` pixel), and the pattern-finding routine `FindPattern.m`. The general call of this latter routine is

```
[err, bim, cim, sim, xc, yc, bc, cc, sc, len, imm] = FindPattern(im,mask,sup,bck,size,tsh,fun,flag)
```

Before explaining the meaning of all the variables, I will describe here briefly the pattern matching algorithm. Let x_{jk} be the intensity value of the pixel with co-ordinates (j,k) in the original image. The task is to identify and localize pre-defined patterns within the image. Thus, the algorithm has to compare all possible sub-regions of the image with a discrete set of R predefined patterns $p_{jk}^{(r)}$ which shall have the size $(2L+1) \times (2L+1)$ (with $1 \leq r \leq R$ counting the patterns and $-L \leq j \leq L$ and $-L \leq k \leq L$ counting the pixels of the patterns). Additionally, a uniform background pattern b may be super-imposed, and the pattern-matching may be restricted to non-rectangular sub-areas defined by the support matrices $s_{jk}^{(r)}$ of same size as the patterns but having values one and zero only. Furthermore it is assumed that within any given sub-area of the image, only one of the R patterns can be present. Pattern comparison is done in the following way. The algorithm fits, by a least-square method, each of the R patterns (plus a flat background) to all possible sub-areas of the image. For every sub-area, the algorithm chooses the pattern yielding minimal least-square error to be the most likely pattern present in the given sub-area. Thus, for any given sub-area of the image x with pixels $m-L \leq j \leq m+L$ and $n-L \leq k \leq n+L$, the algorithm tries to find $2R$ parameters $c_{jk}^{(r)}$ and $d_{mn}^{(r)}$ so that the least-square errors $e_{mn}^{(r)}$,

$$e_{mn}^{(r)} = \sum_{j=-L}^L \sum_{k=-L}^L s_{jk}^{(r)} \left(x_{m+j, n+k} - c_{mn}^{(r)} p_{jk}^{(r)} - d_{mn}^{(r)} b_{jk} \right)^2, \quad (1)$$

are minimized. Subsequently, it is assumed that the patterns $p_{jk}^{(r)}$ as well as the background pattern b_{jk} are all square normalized so that

$$\sum_{j=-L}^L \sum_{k=-L}^L s_{jk}^{(r)} \left(p_{jk}^{(r)} \right)^2 = 1 \text{ and } \sum_{j=-L}^L \sum_{k=-L}^L s_{jk}^{(r)} \left(b_{jk} \right)^2 = 1. \quad (2)$$

By differentiating with respect to the coefficients $c_{mn}^{(r)}$ and $d_{mn}^{(r)}$, these conditions lead to the $2R$ equations

$$\begin{aligned}\frac{\partial e_{mn}^{(r)}}{\partial c_{mn}^{(r)}} &= \sum_{j=-L}^L \sum_{k=-L}^L s_{jk} \left(x_{m+j, n+k} - c_{mn}^{(r)} p_{jk}^{(r)} - d_{mn}^{(r)} b_{jk} \right) p_{jk}^{(r)} = 0, \\ \frac{\partial e_{mn}^{(r)}}{\partial d_{mn}^{(r)}} &= \sum_{j=-L}^L \sum_{k=-L}^L s_{jk} \left(x_{m+j, n+k} - c_{mn}^{(r)} p_{jk}^{(r)} - d_{mn}^{(r)} b_{jk} \right) b_{jk} = 0,\end{aligned}\tag{3}$$

with $1 \leq r \leq R$. Introducing the abbreviations

$$\begin{aligned}X_{mn} &\equiv \sum_{j=-L}^L \sum_{k=-L}^L s_{jk} x_{m+j, n+k} b_{jk}, \\ Q_{mn}^{(r)} &\equiv \sum_{j=-L}^L \sum_{k=-L}^L s_{jk} x_{m+j, n+k} p_{jk}^{(r)}, \\ P^{(r)} &\equiv \sum_{j=-L}^L \sum_{k=-L}^L s_{jk} p_{jk}^{(r)} b_{jk}\end{aligned}\tag{4}$$

the two equations can be rewritten in matrix form as

$$\begin{pmatrix} 1 & P^{(r)} \\ P^{(r)} & 1 \end{pmatrix} \begin{pmatrix} c_{mn}^{(r)} \\ d_{mn}^{(r)} \end{pmatrix} = \begin{pmatrix} Q_{mn}^{(r)} \\ X_{mn} \end{pmatrix}\tag{5}$$

with the explicit solution

$$\begin{pmatrix} c_{mn}^{(r)} \\ d_{mn}^{(r)} \end{pmatrix} = \begin{pmatrix} 1 & P^{(r)} \\ P^{(r)} & 1 \end{pmatrix}^{-1} \begin{pmatrix} Q_{mn}^{(r)} \\ X_{mn} \end{pmatrix} = \frac{1}{1 - (P^{(r)})^2} \begin{pmatrix} 1 & -P^{(r)} \\ -P^{(r)} & 1 \end{pmatrix} \begin{pmatrix} Q_{mn}^{(r)} \\ X_{mn} \end{pmatrix}.\tag{6}$$

The square normalization of the patterns, together with the condition that all pixel values of the patterns are non-negative (and at least one pixel value positive), assures that $0 < P^{(r)} < 1$ and that the solution is well-defined and real. With the coefficients $c_{mn}^{(r)}$ and $b_{mn}^{(r)}$ explicitly known, the R errors $e_{mn}^{(r)}$ are calculated as

$$e_{mn}^{(r)} = (X^2)_{mn} - \frac{(Q_{mn}^{(r)})^2 + (X_{mn})^2 - 2P^{(r)} Q_{mn}^{(r)} X_{mn}}{1 - (P^{(r)})^2}\tag{7}$$

where the additional abbreviation

$$(X^2)_{mn} \equiv \sum_{j=-L}^L \sum_{k=-L}^L s_{jk} x_{m+j, n+k}^2\tag{8}$$

was introduced. The beauty of equations (6) through (8) is that they involve only two-dimensional convolutions of the image x with the patterns $p^{(r)}$ and b , which can be

calculated efficiently by using fast Fourier transforms. Thus, the flow of the image analysis algorithm is summarized as follows:

1. Calculate the $R+1$ two-dimensional convolutions of the image x with the R patterns $p^{(r)}$ and the background pattern b , see Eqs.(4).
2. Calculate the $2R$ “coefficient images” $c^{(r)}$ and $d^{(r)}$ according to Eq.(6).
3. Calculate the R “error images” $e^{(r)}$ according to Eq.(7), involving the calculation of the “squared image” X^2 .
4. For all positions (m,n) , the pattern with minimum error $e_{mn}^{(r)}$ is chosen as the most likely pattern for that position. Thus, two new images \tilde{c} and \tilde{e} are generated with values \tilde{c}_{mn} and \tilde{e}_{mn} composed by those values $c_{mn}^{(r)}$ and $e_{mn}^{(r)}$ having minimum $e_{mn}^{(r)}$.
5. Finally, pattern positions are localized by asking for positions (m,n) where the ratio $\tilde{c}_{mn}/\sqrt{\tilde{e}_{mn}}$ exceeds some predefined value κ . A good value for κ yielding excellent pattern recognition is close to one.

Now, we can specify the meaning of the input and output variables of **FindPattern.m**:

Input variables:

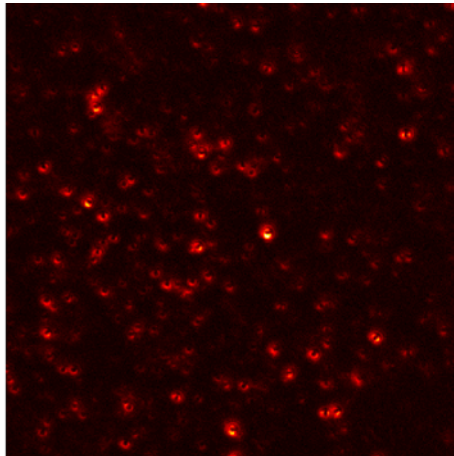
im	– measured image
mask	– 3D stack of model patterns
sup	– support of pattern matching, see s_{jk} above; usually a square or circular disk
bck	– background b_{jk} , usually the same as sup
size	– a threshold parameter which can be used to make the pattern recognition more discriminating for suppressing false positives (default 1)
tsh	– threshold value κ , see above (default 1).
fun	– string with function for deciding a match, default is <code>'cim>tsh*sqrt(err)'</code> , where cim is $c_{mn}^{(r)}$ and err is $e_{mn}^{(r)}$ from above.
flag	– if flag is 1, then pattern matching is suppressed at the image borders within a stripe of half the width of the model images; this is important to prevent false recognitions in the border region (default 1).

Output variables:

err	– error image $\min_r \left(e_{jk}^{(r)} \right)$
bim	– $\min_{e_{jk}^{(r)}} \left(d_{jk}^{(r)} \right)$
cim	– $\min_{e_{jk}^{(r)}} \left(c_{jk}^{(r)} \right)$
sim	– $\min_{e_{jk}^{(r)}} \left(r \right)$
xc, yc	– center coordinates of found patterns
bc	– corresponding values of bim
cc	– corresponding values of cim
sc	– corresponding pattern index
len	– number of found patterns
imm	– reconstructed image with found model patterns

Example

As example consider the following defocused single-molecule image:

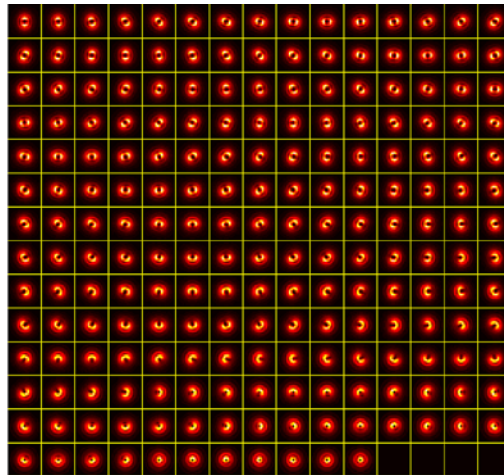


The parameters used for the pattern generation are:

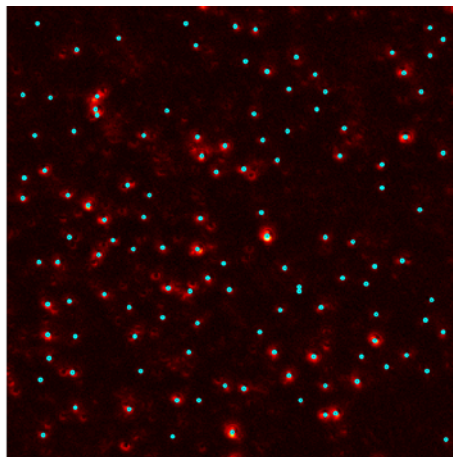
```
z = 0;  
NA = 1.40;  
n0 = 1.52;  
n = 1.49;  
n1 = 1.0;  
d0 = [];  
d = 0.01;  
d1 = [];  
lamem = 0.57;  
mag = 140;  
focus = 0.65;  
atf = [];  
ring = [];  
pixel = 16;  
pic = 0;  
be_res = [];
```

```
al_res = [];
nn = [];
```

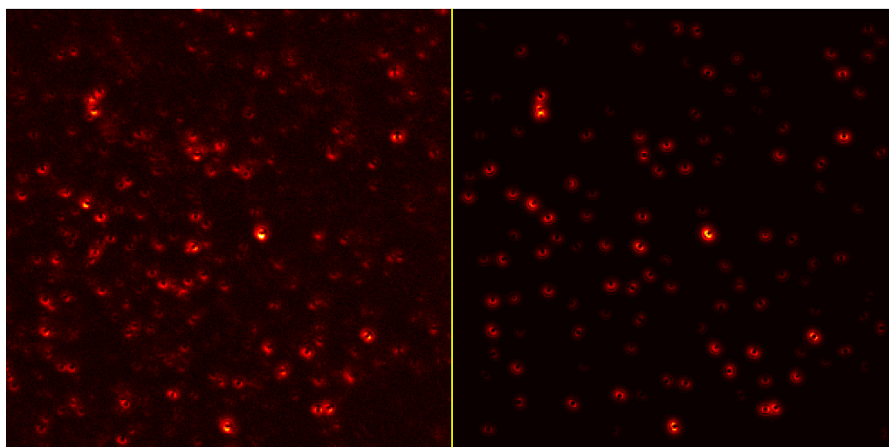
The resulting model patterns are displayed by `CombineImages(model.mask,15,15):`



After applying the pattern matching algorithm, one can display the found coordinates of the patterns with `min(im); hold on; plot(xc,yc,'oc'); hold off`



Or one can display, the original and the reconstructed image by `CombineImages(cat(3,im,imm),1,2):`



The index of the corresponding pattern is stored in the vector `sc`, thus for the j_{th} pattern, the best matching angular orientations are `model.theta(sc(j))` and `model.phi(sc(j))`.